

Graphene and shielding

SiO Graphene project

Lennart Hasselgren
Senior EMC Engineer



Content

- Project scope
- Shielding challenge
 - New material
- SE measurement technique
- The future

Participants

- Institute
 - RISE IVF, Mölndal
 - RISE, Linköping
 - RISE, Borås
- EMC technology
 - EMC Services
- Manufacturers, products
 - Atlas Copco Industrial Technique
 - Megger Sweden
- Manufacturers, material
 - Graphmatech
 - Biofiber Tech Sweden
 - Meva Energy

Med stöd från



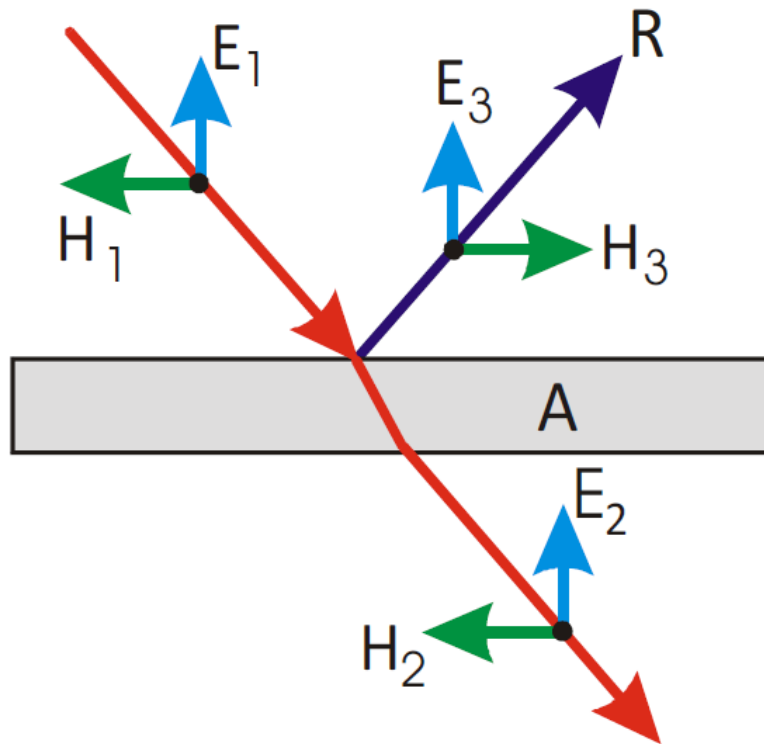
Strategiska
innovations-
program

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Project scope

- Shielding for EMC design
 - Main interest for manufacturers: 30 – 1000 MHz
- Replacement of existing NI-plating material
 - environmental issue
- Replacement of metal enclosure
 - cost and weight issue
- Graphene inclusion in polyimide with kept performance
 - How much is needed?
 - Mechanical performance
- Will be demonstrated in actual products from Atlas Copco Industrial Technique and Megger Sweden
- *How to measure – today focus*

Shielding definition – traditional theoretical approach



$$SE = E_2^2 / E_1^2 \text{ or } SE = R + A \text{ [dB]}$$

(shielding effectiveness)

R = Reflection loss

A = Absorption loss

R = f (wave impedance, material, frequency)

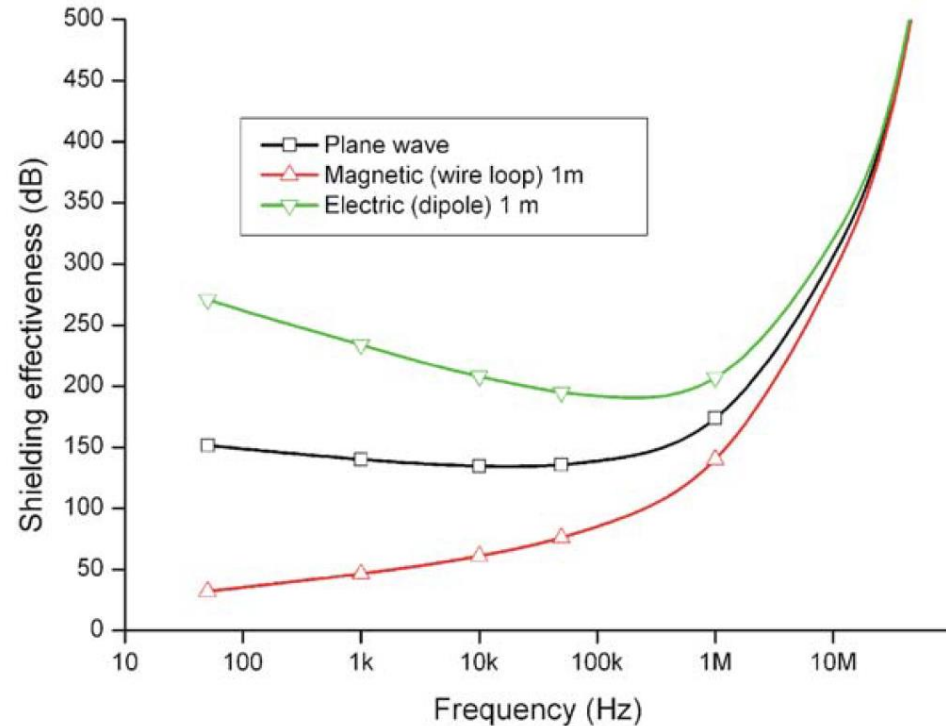
A = f (material, thickness, frequency)

Theoretical approach infinitely large plate
The multiple reflection parameter, M, is often neglected

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Shielding – theoretical calculation example



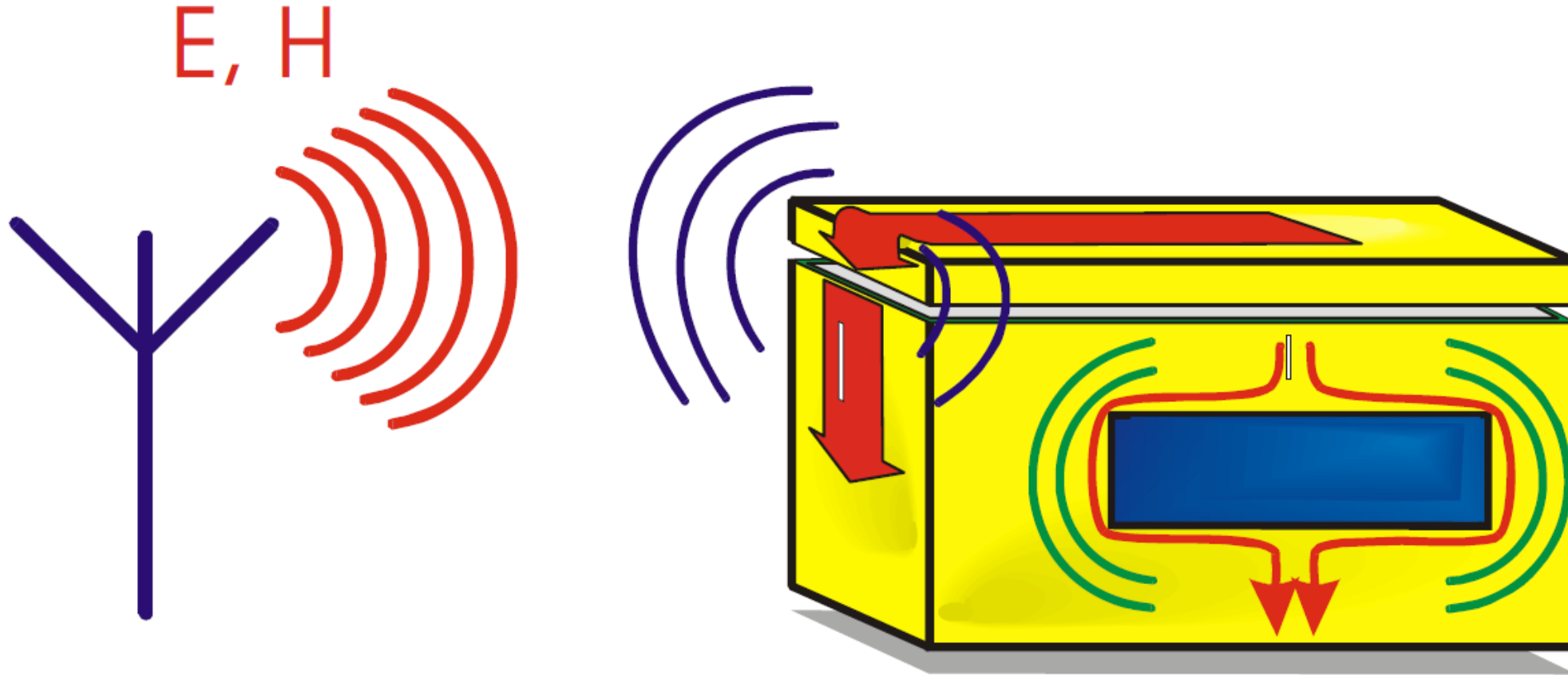
Shielding effectiveness for 0.5 mm Al

Ref.: HW Ott

- Only provides material influence
 - Conclusion from graph: the material is normally not a big issue
 - Not a valid assumption for Graphene?
- Matching interfaces not included
- Results at low frequency not valid
 - Geometry parameters needed
 - Often lower values for magnetic shielding

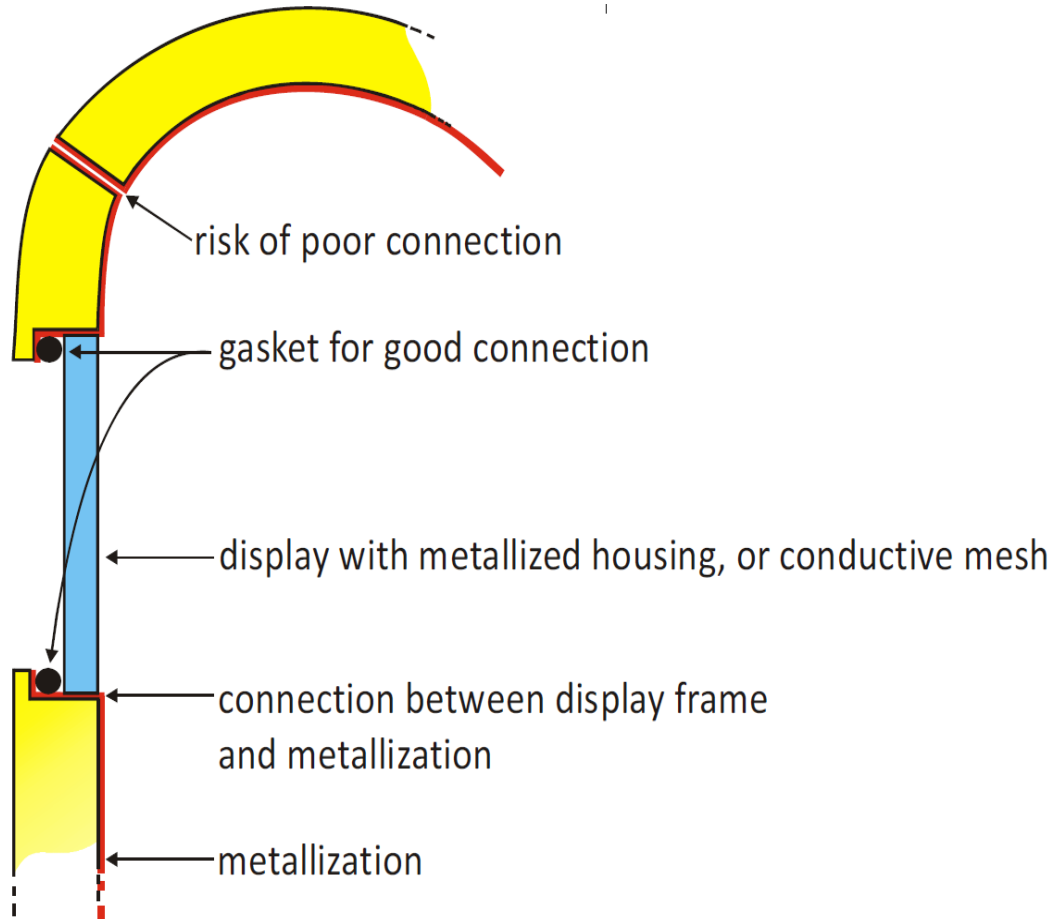
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Shielding leakage - the dominant aspect



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Coated parts – design challenge



Compatibility between

- 2 shielding parts
- Other mating surfaces
- Shielding connectors
- Filter connection (for external filtered interface)

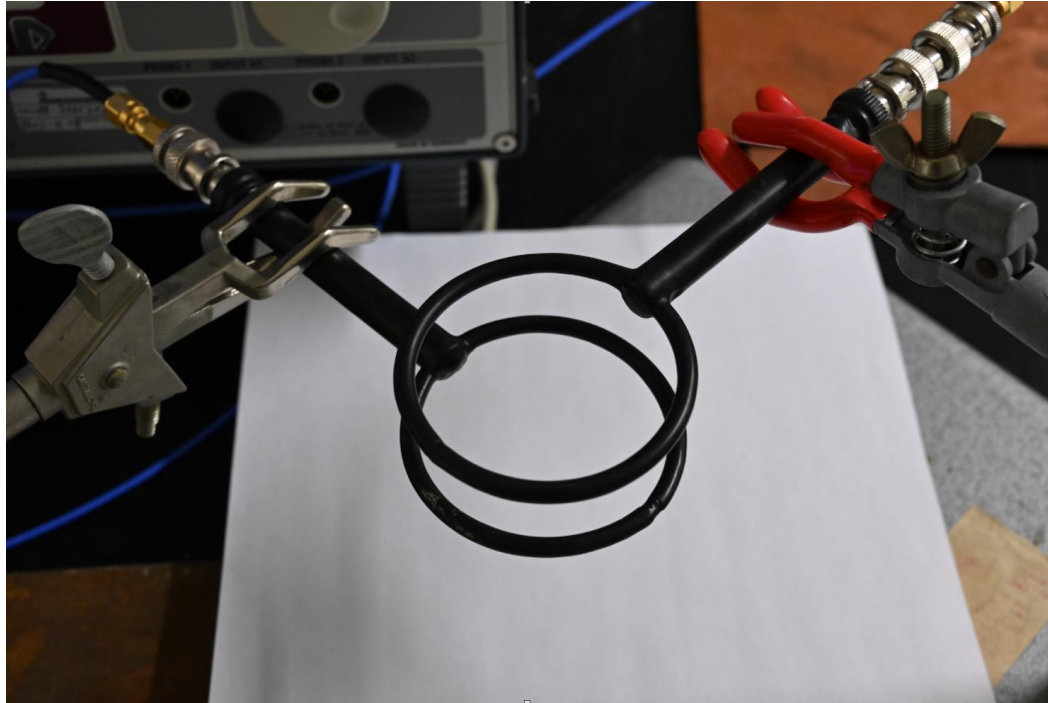
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Measurement technique

- 3 levels
 - Material level – survey method
 - Material level – test fixture
 - Product level
 - Standardized method – compare EUTs with CISPR 16 emission method
 - What do we find from this
 - Reference method with internal generator?
 - Tailored test object?
- Resistance measurement methods
 - Material level – LF measurement of resistance
 - Suitable for quick selection and evaluation

Material level test – survey method

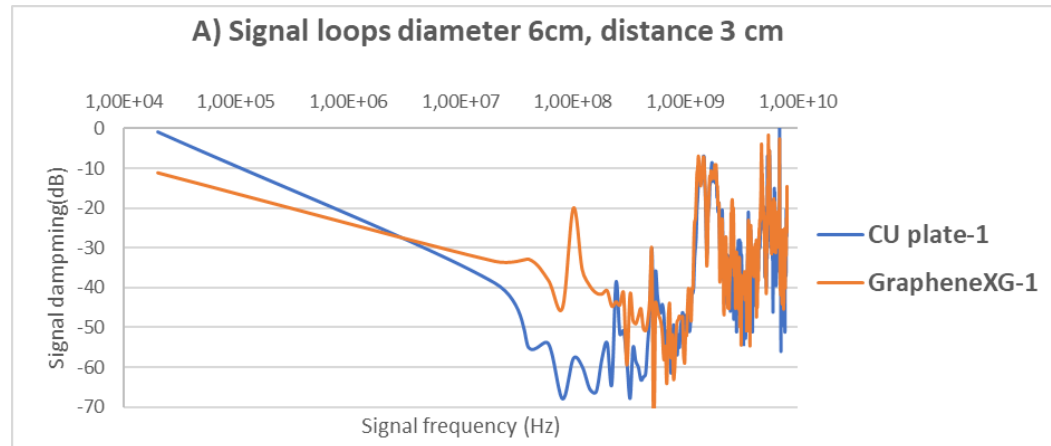


- Test setup using loop antennas
 - 1 – 1000 MHz OK
- Quick simple method
 - Near field measurement
 - Impact on antenna factor?
 - Edge leakage?
 - Antenna distance not so critical
 - Ref: “A method of accurately measuring shielding effectiveness of materials in electronic products” (Douglas C. Smith)

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First results #1 – survey method (loops)

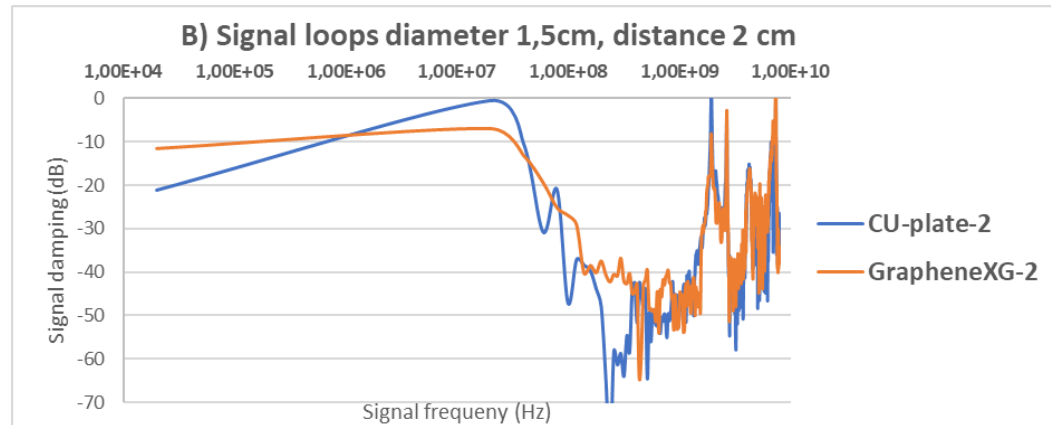


- Test setup using loop antennas
 - 20 kHz – 8 GHz
- Comparison with reference Cu plate
- Some resonances
 - Mainly at > 1 GHz – loop behavior
 - Below 1 GHz – setup resonances?
- Material XG-1
 - ca 20 dB difference from Cu
 - Resonance at 100 MHz

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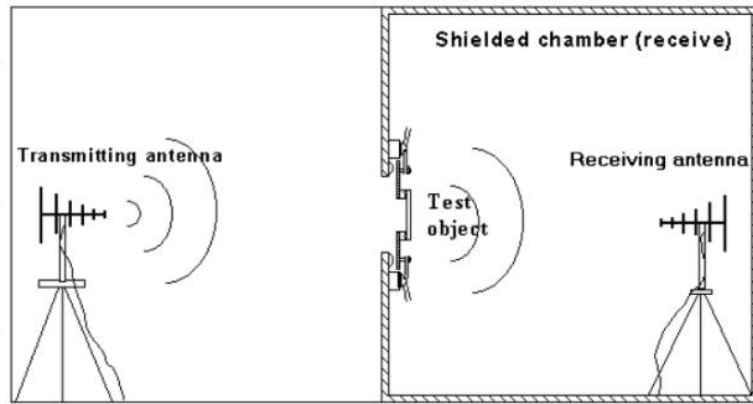
First results #2 – survey method (loops)



- Test setup using loop antennas
 - 20 kHz – 8 GHz
- Comparison with reference Cu plate
- Much smaller probe
 - Poor resolution < 100 MHz
 - Less resonances
 - Less coupling loop-mtrl?
 - Less edge leakage?
 - Mainly at > 3 GHz – loop behavior
- Material XG-2
 - Approx. same as Cu
 - Resolution probably limited

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Material level test – Mode Stirred Chamber (MSC)



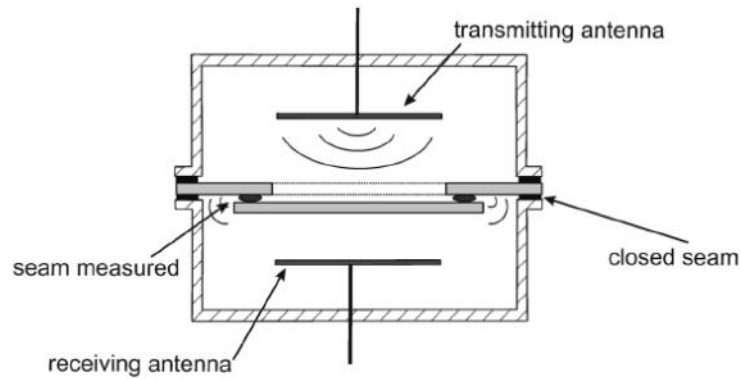
Shielding effectiveness measurements according to IEEE-STD-299, principle.



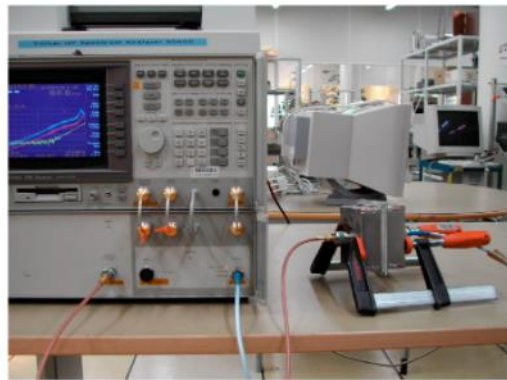
- Test setup using mode-stirred chamber
- High quality method
 - Far field measurement
 - but only useable for approx. $f > 500$ MHz
- Complex setup, special equipment
 - IEC 61726 (passive component test)
 - MIL STD-285 and MIL-DTL 83528 are only using fixed antenna
- Example showing gasket measurement
 - Source: KI report 2004:2E “Ageing of shielding joints” (Lena Sjögren)

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Material level test – small test fixture

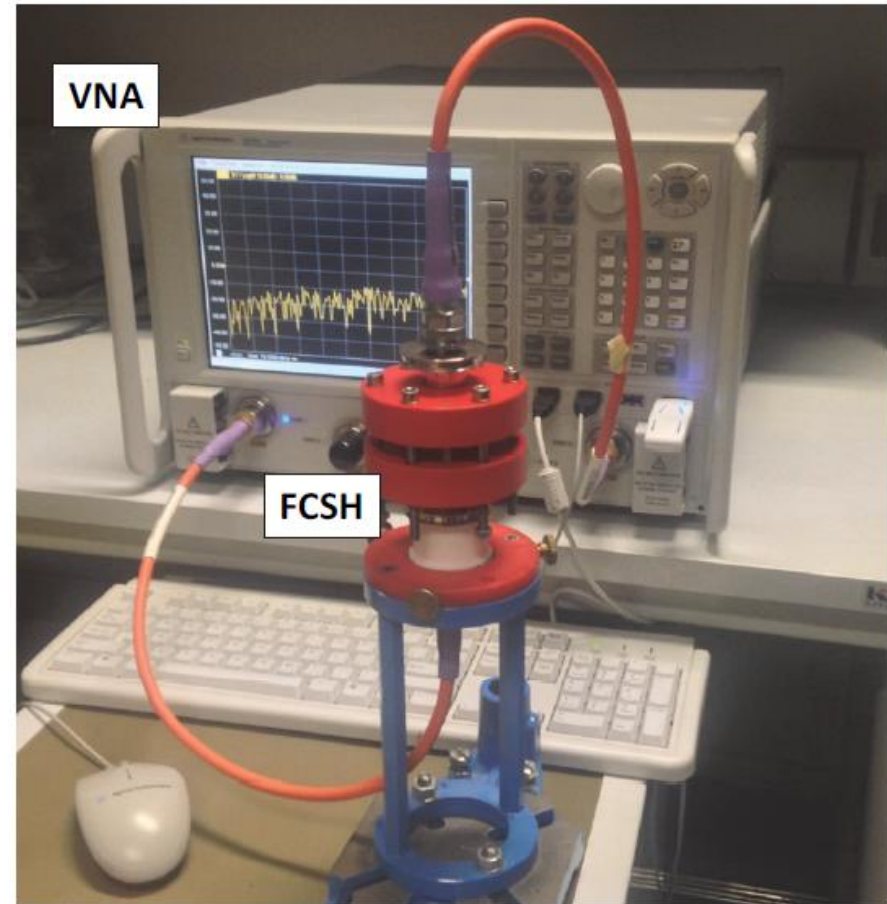


Shielded box for shielding effectiveness measurements in the near field.



Gasket measurement

Source: KI report 2004:2E "Ageing of shielding joints" (Lena Sjögren)

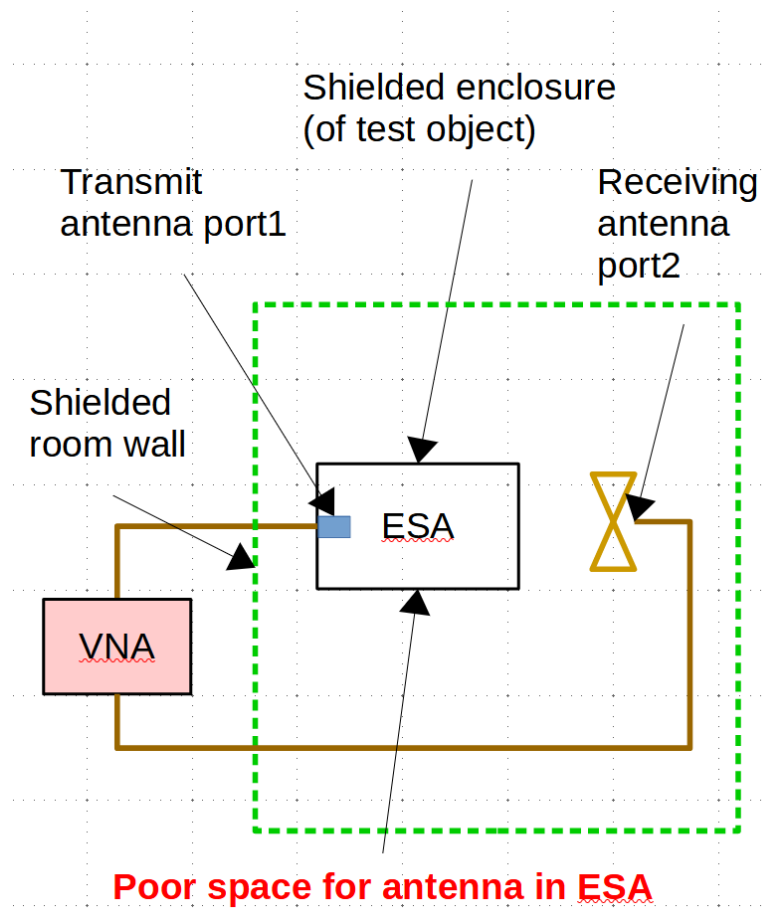


Source: "RF shielding performance of thin flexible graphene nanoplatelets-based papers" (Tamburrano et al), IEEE 2014

Test fixture aspects

- Test setup using small test fixture
 - FCSH = Flanged Coaxial Sample Holder
- Higher quality method
 - Near field measurement
 - Low resolution < 100 MHz
 - E or H-field probes?
- Relatively simple equipment
- Standard ASTM D4935-18 (intended for gaskets) can be used as reference

Shielding test method, product level

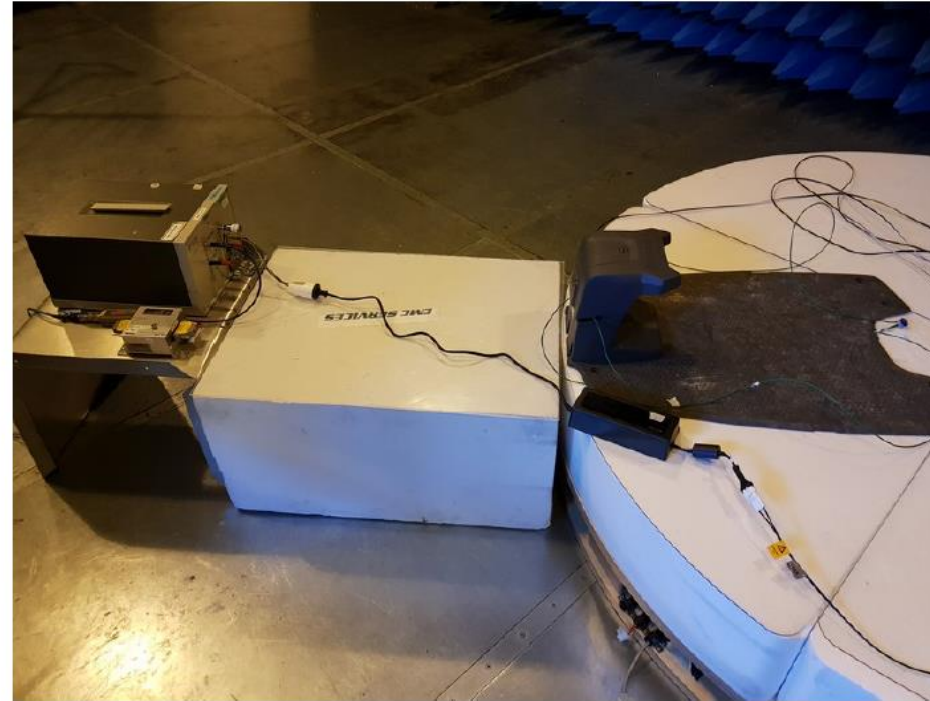


- Approach:
 - Measure the attenuation through the enclosure
- Alternatives:
 - Figure: Standard IEEE 299 for radiated cabinet measurement
 - CISPR25 method for conducted measurements (transfer methods)
 - Many IEC standards for cables and connectors
 - Not relevant
- Cons for IEEE 299:
 - 30-300 MHz not covered for enclosures
 - Interfaces of connectors and cables may be missed in IEEE method
 - Electronic HW influence not included

Product level EMC testing, EN standard



Radiated emission



Conducted emission

EUT placed on specified height from GRP – tabletop or floor standing

Handling resonances in measurement

Smoothing of result may be made in 3 domains

- Geometry domain: mode stirring
 - Averaging of angle of incidence by changing the chamber
- Frequency domain
 - Smoothing by averaging over a frequency bandwidth
- Antenna domain
 - Averaging by turning the object

Future projects

- SiO Graphene program welcomes new initiatives
- In particular with focus on electronics
- Ideas?

Response from audience

- Tips från coacherna?